

**Notice of References Cited**

Application/Control No.

10/015,389

Applicant(s)/Patent Under  
Reexamination  
BAKER ET AL.

Examiner

Rachel B. Kapust

Art Unit

1647

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	WO 00/00610	01-2000	WO	LAL et al.	C12N 15/12
	O					
	P					
	Q					
	R					
	S					
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Alignment of SEQ ID NO: 139 and SEQ ID NO: 158 from WO 00/00610
	V	Alignment of SEQ ID NO: 140 and SEQ ID NO: 24 from WO 00/00610
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